

<b>Notice of References Cited</b>	Application/Control No. 10/025,584		Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner Hai H. Huynh		Art Unit 3747	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-US 20040226536A1	11-2004	Sakai et al	123/308
*	B	US-2003/0034005 A1	02-2003	Ries-Mueller et al.	123/306
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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